

ABSTRACT OF THE DISCLOSURE

An apparatus for selecting test patterns in accordance with an embodiment of the present invention has a first test pattern selecting module configured to
5 define selected test patterns and unselected test patterns, a fault simulation module configured to simulate whether test patterns detect faults, a weighting module configured to add a weight to each of the first undetected faults, a fault sampling
10 module configured to extract second undetected faults from the first undetected faults given the added weight, and a second test pattern selecting module configured to extract additionally selected test patterns based on the added weight.

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